

SEMITOP<sup>®</sup> 2

### **IGBT** Module

#### SK50GAL065 SK50GAR065

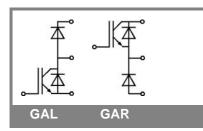
Preliminary Data

#### Features

- Compact design
- One screw mounting
- Heat transfer and isolation through direct copper bonded aluminium oxide ceramic (DCB)
- N-channel homogeneous silicon structure (NPT-Non-Punch-Through IGBT)
- Low tail current with low
- temperature dependenceLow treshold voltage

#### **Typical Applications**

- Switching (not for linear use)
- Inverter
- Switched mode power supplies
- UPS



Absolute	Maximum Ratings	T <sub>s</sub> =	25 °C, unless otherwise sp	pecifie
Symbol	Conditions		Values	Units
IGBT				
V <sub>CES</sub>	T <sub>j</sub> = 25 °C T <sub>i</sub> = 125 °C		600	V
I <sub>C</sub>	T <sub>j</sub> = 125 °C	T <sub>s</sub> = 25 °C	54	Α
		T <sub>s</sub> = 80 °C	40	Α
I <sub>CRM</sub>	I <sub>CRM</sub> = 2 x I <sub>Cnom</sub>		60	А
V <sub>GES</sub>			± 20	V
t <sub>psc</sub>	$V_{CC}$ = 300 V; $V_{GE} \le 20$ V;	T <sub>i</sub> = 125 °C	10	μs
F	VCES < 600 V	,		
Inverse D	Diode			
I <sub>F</sub>	T <sub>j</sub> = 150 °C	T <sub>s</sub> = 25 °C	57	А
		T <sub>s</sub> = 80 °C	38	Α
I <sub>FRM</sub>	I <sub>FRM</sub> = 2 x I <sub>Fnom</sub>		100	А
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; half sine wave	T <sub>j</sub> = 150 °C	440	А
Freewhee	eling Diode			
I <sub>F</sub>	T <sub>j</sub> = 150 °C	T <sub>s</sub> = 25 °C	57	А
		T <sub>s</sub> = 80 °C	38	А
I <sub>FRM</sub>			100	А
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; half sine wave	T <sub>j</sub> = 150 °C	440	А
Module				
I <sub>t(RMS)</sub>				А
T <sub>vj</sub>			-40 +150	°C
T <sub>stg</sub>			-40 +125	°C
V <sub>isol</sub>	AC, 1 min.		2500	V

Characteristics T <sub>s</sub> =			25 °C, unless otherwise specified				
Symbol	Conditions		min.	typ.	max.	Units	
IGBT							
V <sub>GE(th)</sub>	$V_{GE} = V_{CE}, I_C = 1,4 \text{ mA}$		3	4	5	V	
I <sub>CES</sub>	$V_{GE}$ = 0 V, $V_{CE}$ = $V_{CES}$	T <sub>j</sub> = 25 °C			0,0044	mA	
I <sub>GES</sub>	V <sub>CE</sub> = 0 V, V <sub>GE</sub> = 20 V	T <sub>j</sub> = 25 °C			240	nA	
V <sub>CE0</sub>		T <sub>j</sub> = 25 °C		1,1		V	
		T <sub>j</sub> = 125 °C		1,1		V	
r <sub>CE</sub>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25°C		15		mΩ	
		T <sub>j</sub> = 125°C		19		mΩ	
V <sub>CE(sat)</sub>	I <sub>Cnom</sub> = 60 A, V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25°C <sub>chiplev.</sub>		2	2,5	V	
		T <sub>j</sub> = 125°C <sub>chiplev.</sub>		2,2		V	
C <sub>ies</sub>				3,2		nF	
C <sub>oes</sub>	$V_{CE}$ = 25, $V_{GE}$ = 0 V	f = 1 MHz		0,3		nF	
C <sub>res</sub>				0,18		nF	
t <sub>d(on)</sub>				60	80	ns	
t,	R <sub>Gon</sub> = 16 Ω	V <sub>CC</sub> = 300V		30	40	ns	
E <sub>on</sub>		I <sub>Cnom</sub> = 40A		1,1	1,4	mJ	
t <sub>d(off)</sub>	R <sub>Goff</sub> = 16 Ω	T <sub>j</sub> = 125 °C		220	280	ns	
t <sub>f</sub>		V <sub>GE</sub> =±15V		20	26	ns	
E <sub>off</sub>				0,7	0,9	mJ	
R <sub>th(j-s)</sub>	per IGBT				0,85	K/W	

1



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  (NET Num Provide Theorem 100PT)
  - (NPT-Non-Punch-Through IGBT)
- Low tail current with low temperature dependence
- Low treshold voltage

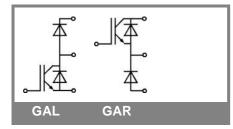
#### **Typical Applications**

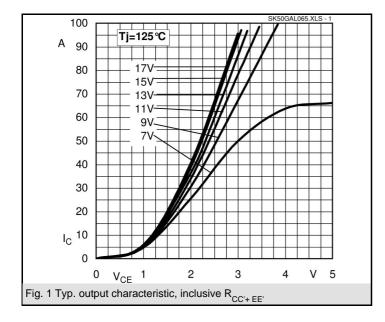
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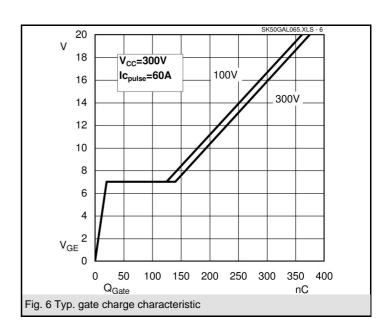
Characteristics							
Symbol	Conditions		min.	typ.	max.	Units	
Inverse D	Diode						
$V_F = V_{EC}$	I <sub>Fnom</sub> = 30 A; V <sub>GE</sub> = 0 V	T <sub>j</sub> = 25 °C <sub>chiplev.</sub>		1,3	1,5	V	
		T <sub>j</sub> = 150 °C <sub>chiplev.</sub>		1,2	1,45	V	
V <sub>F0</sub>		T <sub>j</sub> = 25 °C				V	
		T <sub>j</sub> = 125 °C		0,85	0,9	V	
r <sub>F</sub>		T <sub>j</sub> = 25 °C				mΩ	
		T <sub>j</sub> = 125 °C		9	16	mΩ	
I <sub>RRM</sub>	I <sub>Fnom</sub> = 30 A	T <sub>i</sub> = 125 °C		22		Α	
Q <sub>rr</sub>	di/dt = -500 A/µs	,		2,2		μC	
E <sub>rr</sub>	V <sub>CC</sub> = 300V			0,2		mJ	
R <sub>th(j-s)D</sub>	per diode				1,2	K/W	
Freewhee	eling Diode						
$V_F = V_{EC}$	I <sub>Fnom</sub> = 30 A; V <sub>GE</sub> = 0 V	T <sub>j</sub> = 25 °C <sub>chiplev.</sub>		1,3	1,5	V	
		T <sub>j</sub> = 125 °C <sub>chiplev.</sub>		1,2	1,45	V	
V <sub>F0</sub>		T <sub>j</sub> = 125 °C		0,85	0,9	V	
r <sub>F</sub>		T <sub>i</sub> = 125 °C		9	16	V	
I <sub>RRM</sub>	I <sub>Fnom</sub> = 30 A	T <sub>i</sub> = 125 °C		22		Α	
Q <sub>rr</sub>	di/dt = -500 A/µs			2,2		μC	
E <sub>rr</sub>	V <sub>R</sub> =300V			0,2		mJ	
$R_{th(j-s)FD}$	per diode				1,2	K/W	
M <sub>s</sub>	to heat sink				2	Nm	
w				19		g	

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.







3

#### UL recognized file

no. E 63 532

